


<b>Search Notes</b> 	<b>Application/Control No.</b> 10560050	<b>Applicant(s)/Patent Under Reexamination</b> OHKI ET AL.
	<b>Examiner</b> KRISTEN C MATTER	<b>Art Unit</b> 3771

SEARCHED			
Class	Subclass	Date	Examiner
128	203.12, 203.15, 203.21-203.24	10/16/08	KCM

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor name search	10/16/08	KCM

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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